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Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details

Product Status	Obsolete
Number of LABs/CLBs	128300
Number of Logic Elements/Cells	340000
Total RAM Bits	19456000
Number of I/O	600
Number of Gates	-
Voltage - Supply	0.87V ~ 0.93V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	1517-BBGA, FCBGA
Supplier Device Package	1517-FBGA (40x40)
Purchase URL	https://www.e-xfl.com/product-detail/intel/5sgxma3k2f40i2n

Table 8 shows the transceiver power supply voltage requirements for various conditions.

Table 8. Transceiver Power Supply Voltage Requirements

Conditions	Core Speed Grade	VCCR_GXB & VCCT_GXB ⁽²⁾	VCCA_GXB	VCCH_GXB	Unit
If BOTH of the following conditions are true: ■ Data rate > 10.3 Gbps. ■ DFE is used.	All	1.05			
If ANY of the following conditions are true ⁽¹⁾ : ■ ATX PLL is used. ■ Data rate > 6.5Gbps. ■ DFE (data rate ≤ 10.3 Gbps), AEQ, or EyeQ feature is used.	All	1.0	3.0	1.5	V
If ALL of the following conditions are true: ■ ATX PLL is not used. ■ Data rate ≤ 6.5Gbps. ■ DFE, AEQ, and EyeQ are not used.	C1, C2, I2, and I3YY C2L, C3, C4, I2L, I3, I3L, and I4	0.90 0.85	2.5 2.5		

Notes to Table 8:

- (1) Choose this power supply voltage requirement option if you plan to upgrade your design later with any of the listed conditions.
- (2) If the VCCR_GXB and VCCT_GXB supplies are set to 1.0 V or 1.05 V, they cannot be shared with the VCC core supply. If the VCCR_GXB and VCCT_GXB are set to either 0.90 V or 0.85 V, they can be shared with the VCC core supply.

DC Characteristics

This section lists the supply current, I/O pin leakage current, input pin capacitance, on-chip termination tolerance, and hot socketing specifications.

Supply Current

Supply current is the current drawn from the respective power rails used for power budgeting. Use the Excel-based Early Power Estimator (EPE) to get supply current estimates for your design because these currents vary greatly with the resources you use.

-  For more information about power estimation tools, refer to the *PowerPlay Early Power Estimator User Guide* and the *PowerPlay Power Analysis* chapter in the *Quartus II Handbook*.

Table 11. OCT Calibration Accuracy Specifications for Stratix V Devices⁽¹⁾ (Part 2 of 2)

Symbol	Description	Conditions	Calibration Accuracy				Unit
			C1	C2,I2	C3,I3, I3YY	C4,I4	
50- Ω R_S	Internal series termination with calibration (50- Ω setting)	$V_{CCIO} = 3.0, 2.5, 1.8, 1.5, 1.2 \text{ V}$	± 15	± 15	± 15	± 15	%
34- Ω and 40- Ω R_S	Internal series termination with calibration (34- Ω and 40- Ω setting)	$V_{CCIO} = 1.5, 1.35, 1.25, 1.2 \text{ V}$	± 15	± 15	± 15	± 15	%
48- Ω , 60- Ω , 80- Ω , and 240- Ω R_S	Internal series termination with calibration (48- Ω , 60- Ω , 80- Ω , and 240- Ω setting)	$V_{CCIO} = 1.2 \text{ V}$	± 15	± 15	± 15	± 15	%
50- Ω R_T	Internal parallel termination with calibration (50- Ω setting)	$V_{CCIO} = 2.5, 1.8, 1.5, 1.2 \text{ V}$	-10 to +40	-10 to +40	-10 to +40	-10 to +40	%
20- Ω , 30- Ω , 40- Ω , 60- Ω , and 120- Ω R_T	Internal parallel termination with calibration (20- Ω , 30- Ω , 40- Ω , 60- Ω , and 120- Ω setting)	$V_{CCIO} = 1.5, 1.35, 1.25 \text{ V}$	-10 to +40	-10 to +40	-10 to +40	-10 to +40	%
60- Ω and 120- Ω R_T	Internal parallel termination with calibration (60- Ω and 120- Ω setting)	$V_{CCIO} = 1.2$	-10 to +40	-10 to +40	-10 to +40	-10 to +40	%
25- Ω $R_{S_left_shift}$	Internal left shift series termination with calibration (25- Ω $R_{S_left_shift}$ setting)	$V_{CCIO} = 3.0, 2.5, 1.8, 1.5, 1.2 \text{ V}$	± 15	± 15	± 15	± 15	%

Note to Table 11:

- (1) OCT calibration accuracy is valid at the time of calibration only.

Table 12 lists the Stratix V OCT without calibration resistance tolerance to PVT changes.

Table 12. OCT Without Calibration Resistance Tolerance Specifications for Stratix V Devices (Part 1 of 2)

Symbol	Description	Conditions	Resistance Tolerance				Unit
			C1	C2,I2	C3, I3, I3YY	C4, I4	
25- Ω R , 50- Ω R_S	Internal series termination without calibration (25- Ω setting)	$V_{CCIO} = 3.0 \text{ and } 2.5 \text{ V}$	± 30	± 30	± 40	± 40	%
25- Ω R_S	Internal series termination without calibration (25- Ω setting)	$V_{CCIO} = 1.8 \text{ and } 1.5 \text{ V}$	± 30	± 30	± 40	± 40	%
25- Ω R_S	Internal series termination without calibration (25- Ω setting)	$V_{CCIO} = 1.2 \text{ V}$	± 35	± 35	± 50	± 50	%

Internal Weak Pull-Up Resistor

Table 16 lists the weak pull-up resistor values for Stratix V devices.

Table 16. Internal Weak Pull-Up Resistor for Stratix V Devices^{(1), (2)}

Symbol	Description	V _{CCIO} Conditions (V) ⁽³⁾	Value ⁽⁴⁾	Unit
R _{PU}	Value of the I/O pin pull-up resistor before and during configuration, as well as user mode if you enable the programmable pull-up resistor option.	3.0 ±5%	25	kΩ
		2.5 ±5%	25	kΩ
		1.8 ±5%	25	kΩ
		1.5 ±5%	25	kΩ
		1.35 ±5%	25	kΩ
		1.25 ±5%	25	kΩ
		1.2 ±5%	25	kΩ

Notes to Table 16:

- (1) All I/O pins have an option to enable the weak pull-up resistor except the configuration, test, and JTAG pins.
- (2) The internal weak pull-down feature is only available for the JTAG TCK pin. The typical value for this internal weak pull-down resistor is approximately 25 kΩ.
- (3) The pin pull-up resistance values may be lower if an external source drives the pin higher than V_{CCIO}.
- (4) These specifications are valid with a ±10% tolerance to cover changes over PVT.

I/O Standard Specifications

Table 17 through Table 22 list the input voltage (V_{IH} and V_{IL}), output voltage (V_{OH} and V_{OL}), and current drive characteristics (I_{OH} and I_{OL}) for various I/O standards supported by Stratix V devices. These tables also show the Stratix V device family I/O standard specifications. The V_{OL} and V_{OH} values are valid at the corresponding I_{OH} and I_{OL}, respectively.

For an explanation of the terms used in Table 17 through Table 22, refer to “Glossary” on page 65. For tolerance calculations across all SSTL and HSTL I/O standards, refer to Altera knowledge base solution rd07262012_486.

Table 17. Single-Ended I/O Standards for Stratix V Devices

I/O Standard	V _{CCIO} (V)			V _{IL} (V)		V _{IH} (V)		V _{OL} (V)	V _{OH} (V)	I _{OL} (mA)	I _{OH} (mA)
	Min	Typ	Max	Min	Max	Min	Max	Max	Min		
LVTTL	2.85	3	3.15	-0.3	0.8	1.7	3.6	0.4	2.4	2	-2
LVCMOS	2.85	3	3.15	-0.3	0.8	1.7	3.6	0.2	V _{CCIO} - 0.2	0.1	-0.1
2.5 V	2.375	2.5	2.625	-0.3	0.7	1.7	3.6	0.4	2	1	-1
1.8 V	1.71	1.8	1.89	-0.3	0.35 * V _{CCIO}	0.65 * V _{CCIO}	V _{CCIO} + 0.3	0.45	V _{CCIO} - 0.45	2	-2
1.5 V	1.425	1.5	1.575	-0.3	0.35 * V _{CCIO}	0.65 * V _{CCIO}	V _{CCIO} + 0.3	0.25 * V _{CCIO}	0.75 * V _{CCIO}	2	-2
1.2 V	1.14	1.2	1.26	-0.3	0.35 * V _{CCIO}	0.65 * V _{CCIO}	V _{CCIO} + 0.3	0.25 * V _{CCIO}	0.75 * V _{CCIO}	2	-2

Table 18. Single-Ended SSTL, HSTL, and HSUL I/O Reference Voltage Specifications for Stratix V Devices

I/O Standard	V _{CCIO} (V)			V _{REF} (V)			V _{TT} (V)		
	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max
SSTL-2 Class I, II	2.375	2.5	2.625	0.49 * V _{CCIO}	0.5 * V _{CCIO}	0.51 * V _{CCIO}	V _{REF} – 0.04	V _{REF}	V _{REF} + 0.04
SSTL-18 Class I, II	1.71	1.8	1.89	0.833	0.9	0.969	V _{REF} – 0.04	V _{REF}	V _{REF} + 0.04
SSTL-15 Class I, II	1.425	1.5	1.575	0.49 * V _{CCIO}	0.5 * V _{CCIO}	0.51 * V _{CCIO}	0.49 * V _{CCIO}	0.5 * V _{CCIO}	0.51 * V _{CCIO}
SSTL-135 Class I, II	1.283	1.35	1.418	0.49 * V _{CCIO}	0.5 * V _{CCIO}	0.51 * V _{CCIO}	0.49 * V _{CCIO}	0.5 * V _{CCIO}	0.51 * V _{CCIO}
SSTL-125 Class I, II	1.19	1.25	1.26	0.49 * V _{CCIO}	0.5 * V _{CCIO}	0.51 * V _{CCIO}	0.49 * V _{CCIO}	0.5 * V _{CCIO}	0.51 * V _{CCIO}
SSTL-12 Class I, II	1.14	1.20	1.26	0.49 * V _{CCIO}	0.5 * V _{CCIO}	0.51 * V _{CCIO}	0.49 * V _{CCIO}	0.5 * V _{CCIO}	0.51 * V _{CCIO}
HSTL-18 Class I, II	1.71	1.8	1.89	0.85	0.9	0.95	—	V _{CCIO} /2	—
HSTL-15 Class I, II	1.425	1.5	1.575	0.68	0.75	0.9	—	V _{CCIO} /2	—
HSTL-12 Class I, II	1.14	1.2	1.26	0.47 * V _{CCIO}	0.5 * V _{CCIO}	0.53 * V _{CCIO}	—	V _{CCIO} /2	—
HSUL-12	1.14	1.2	1.3	0.49 * V _{CCIO}	0.5 * V _{CCIO}	0.51 * V _{CCIO}	—	—	—

Table 19. Single-Ended SSTL, HSTL, and HSUL I/O Standards Signal Specifications for Stratix V Devices (Part 1 of 2)

I/O Standard	V _{IL(DC)} (V)		V _{IH(DC)} (V)		V _{IL(AC)} (V)	V _{IH(AC)} (V)	V _{OL} (V)	V _{OH} (V)	I _{ol} (mA)	I _{oh} (mA)
	Min	Max	Min	Max						
SSTL-2 Class I	-0.3	V _{REF} – 0.15	V _{REF} + 0.15	V _{CCIO} + 0.3	V _{REF} – 0.31	V _{REF} + 0.31	V _{TT} – 0.608	V _{TT} + 0.608	8.1	-8.1
SSTL-2 Class II	-0.3	V _{REF} – 0.15	V _{REF} + 0.15	V _{CCIO} + 0.3	V _{REF} – 0.31	V _{REF} + 0.31	V _{TT} – 0.81	V _{TT} + 0.81	16.2	-16.2
SSTL-18 Class I	-0.3	V _{REF} – 0.125	V _{REF} + 0.125	V _{CCIO} + 0.3	V _{REF} – 0.25	V _{REF} + 0.25	V _{TT} – 0.603	V _{TT} + 0.603	6.7	-6.7
SSTL-18 Class II	-0.3	V _{REF} – 0.125	V _{REF} + 0.125	V _{CCIO} + 0.3	V _{REF} – 0.25	V _{REF} + 0.25	0.28	V _{CCIO} – 0.28	13.4	-13.4
SSTL-15 Class I	—	V _{REF} – 0.1	V _{REF} + 0.1	—	V _{REF} – 0.175	V _{REF} + 0.175	0.2 * V _{CCIO}	0.8 * V _{CCIO}	8	-8
SSTL-15 Class II	—	V _{REF} – 0.1	V _{REF} + 0.1	—	V _{REF} – 0.175	V _{REF} + 0.175	0.2 * V _{CCIO}	0.8 * V _{CCIO}	16	-16
SSTL-135 Class I, II	—	V _{REF} – 0.09	V _{REF} + 0.09	—	V _{REF} – 0.16	V _{REF} + 0.16	0.2 * V _{CCIO}	0.8 * V _{CCIO}	—	—
SSTL-125 Class I, II	—	V _{REF} – 0.85	V _{REF} + 0.85	—	V _{REF} – 0.15	V _{REF} + 0.15	0.2 * V _{CCIO}	0.8 * V _{CCIO}	—	—
SSTL-12 Class I, II	—	V _{REF} – 0.1	V _{REF} + 0.1	—	V _{REF} – 0.15	V _{REF} + 0.15	0.2 * V _{CCIO}	0.8 * V _{CCIO}	—	—

Table 19. Single-Ended SSTL, HSTL, and HSUL I/O Standards Signal Specifications for Stratix V Devices (Part 2 of 2)

I/O Standard	V _{IL(DC)} (V)		V _{IH(DC)} (V)		V _{IL(AC)} (V)	V _{IH(AC)} (V)	V _{OL} (V)	V _{OH} (V)	I _{ol} (mA)	I _{oh} (mA)
	Min	Max	Min	Max	Max	Min	Max	Min		
HSTL-18 Class I	—	V _{REF} – 0.1	V _{REF} + 0.1	—	V _{REF} – 0.2	V _{REF} + 0.2	0.4	V _{CCIO} – 0.4	8	-8
HSTL-18 Class II	—	V _{REF} – 0.1	V _{REF} + 0.1	—	V _{REF} – 0.2	V _{REF} + 0.2	0.4	V _{CCIO} – 0.4	16	-16
HSTL-15 Class I	—	V _{REF} – 0.1	V _{REF} + 0.1	—	V _{REF} – 0.2	V _{REF} + 0.2	0.4	V _{CCIO} – 0.4	8	-8
HSTL-15 Class II	—	V _{REF} – 0.1	V _{REF} + 0.1	—	V _{REF} – 0.2	V _{REF} + 0.2	0.4	V _{CCIO} – 0.4	16	-16
HSTL-12 Class I	-0.15	V _{REF} – 0.08	V _{REF} + 0.08	V _{CCIO} + 0.15	V _{REF} – 0.15	V _{REF} + 0.15	0.25*	V _{CCIO}	8	-8
HSTL-12 Class II	-0.15	V _{REF} – 0.08	V _{REF} + 0.08	V _{CCIO} + 0.15	V _{REF} – 0.15	V _{REF} + 0.15	0.25*	V _{CCIO}	16	-16
HSUL-12	—	V _{REF} – 0.13	V _{REF} + 0.13	—	V _{REF} – 0.22	V _{REF} + 0.22	0.1*	V _{CCIO}	0.9*	—

Table 20. Differential SSTL I/O Standards for Stratix V Devices

I/O Standard	V _{CCIO} (V)			V _{SWING(DC)} (V)		V _{X(AC)} (V)			V _{SWING(AC)} (V)	
	Min	Typ	Max	Min	Max	Min	Typ	Max	Min	Max
SSTL-2 Class I, II	2.375	2.5	2.625	0.3	V _{CCIO} + 0.6	V _{CCIO} /2 – 0.2	—	V _{CCIO} /2 + 0.2	0.62	V _{CCIO} + 0.6
SSTL-18 Class I, II	1.71	1.8	1.89	0.25	V _{CCIO} + 0.6	V _{CCIO} /2 – 0.175	—	V _{CCIO} /2 + 0.175	0.5	V _{CCIO} + 0.6
SSTL-15 Class I, II	1.425	1.5	1.575	0.2	(1)	V _{CCIO} /2 – 0.15	—	V _{CCIO} /2 + 0.15	0.35	—
SSTL-135 Class I, II	1.283	1.35	1.45	0.2	(1)	V _{CCIO} /2 – 0.15	V _{CCIO} /2	V _{CCIO} /2 + 0.15	2(V _{IH(AC)} – V _{REF})	2(V _{IL(AC)} – V _{REF})
SSTL-125 Class I, II	1.19	1.25	1.31	0.18	(1)	V _{CCIO} /2 – 0.15	V _{CCIO} /2	V _{CCIO} /2 + 0.15	2(V _{IH(AC)} – V _{REF})	—
SSTL-12 Class I, II	1.14	1.2	1.26	0.18	—	V _{REF} – 0.15	V _{CCIO} /2	V _{REF} + 0.15	-0.30	0.30

Note to Table 20:

- (1) The maximum value for V_{SWING(DC)} is not defined. However, each single-ended signal needs to be within the respective single-ended limits (V_{IH(DC)} and V_{IL(DC)}).

Table 21. Differential HSTL and HSUL I/O Standards for Stratix V Devices (Part 1 of 2)

I/O Standard	V _{CCIO} (V)			V _{DIF(DC)} (V)		V _{X(AC)} (V)			V _{CM(DC)} (V)			V _{DIF(AC)} (V)	
	Min	Typ	Max	Min	Max	Min	Typ	Max	Min	Typ	Max	Min	Max
HSTL-18 Class I, II	1.71	1.8	1.89	0.2	—	0.78	—	1.12	0.78	—	1.12	0.4	—
HSTL-15 Class I, II	1.425	1.5	1.575	0.2	—	0.68	—	0.9	0.68	—	0.9	0.4	—

-  You typically use the interactive Excel-based Early Power Estimator before designing the FPGA to get a magnitude estimate of the device power. The Quartus II PowerPlay Power Analyzer provides better quality estimates based on the specifics of the design after you complete place-and-route. The PowerPlay Power Analyzer can apply a combination of user-entered, simulation-derived, and estimated signal activities that, when combined with detailed circuit models, yields very accurate power estimates.
-  For more information about power estimation tools, refer to the *PowerPlay Early Power Estimator User Guide* and the *PowerPlay Power Analysis* chapter in the *Quartus II Handbook*.

Table 23. Transceiver Specifications for Stratix V GX and GS Devices ⁽¹⁾ (Part 2 of 7)

Symbol/ Description	Conditions	Transceiver Speed Grade 1			Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Spread-spectrum downspread	PCIe	—	0 to -0.5	—	—	0 to -0.5	—	—	0 to -0.5	—	%
On-chip termination resistors ⁽²⁾	—	—	100	—	—	100	—	—	100	—	Ω
Absolute V _{MAX} ⁽⁵⁾	Dedicated reference clock pin	—	—	1.6	—	—	1.6	—	—	1.6	V
	RX reference clock pin	—	—	1.2	—	—	1.2	—	—	1.2	
Absolute V _{MIN}	—	-0.4	—	—	-0.4	—	—	-0.4	—	—	V
Peak-to-peak differential input voltage	—	200	—	1600	200	—	1600	200	—	1600	mV
V _{ICM} (AC coupled) ⁽³⁾	Dedicated reference clock pin	1050/1000/900/850 ⁽²⁾			1050/1000/900/850 ⁽²⁾			1050/1000/900/850 ⁽²⁾			mV
	RX reference clock pin	1.0/0.9/0.85 ⁽⁴⁾			1.0/0.9/0.85 ⁽⁴⁾			1.0/0.9/0.85 ⁽⁴⁾			V
V _{ICM} (DC coupled)	HCSL I/O standard for PCIe reference clock	250	—	550	250	—	550	250	—	550	mV
Transmitter REFCLK Phase Noise (622 MHz) ⁽²⁰⁾	100 Hz	—	—	-70	—	—	-70	—	—	-70	dBc/Hz
	1 kHz	—	—	-90	—	—	-90	—	—	-90	dBc/Hz
	10 kHz	—	—	-100	—	—	-100	—	—	-100	dBc/Hz
	100 kHz	—	—	-110	—	—	-110	—	—	-110	dBc/Hz
	≥1 MHz	—	—	-120	—	—	-120	—	—	-120	dBc/Hz
Transmitter REFCLK Phase Jitter (100 MHz) ⁽¹⁷⁾	10 kHz to 1.5 MHz (PCIe)	—	—	3	—	—	3	—	—	3	ps (rms)
R _{REF} ⁽¹⁹⁾	—	—	1800 ±1%	—	—	1800 ±1%	—	—	180 0 ±1%	—	Ω
Transceiver Clocks											
fixedclk clock frequency	PCIe Receiver Detect	—	100 or 125	—	—	100 or 125	—	—	100 or 125	—	MHz

Table 23. Transceiver Specifications for Stratix V GX and GS Devices ⁽¹⁾ (Part 3 of 7)

Symbol/ Description	Conditions	Transceiver Speed Grade 1			Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Reconfiguration clock (mgmt_clk_clk) frequency	—	100	—	125	100	—	125	100	—	125	MHz
Receiver											
Supported I/O Standards	—	1.4-V PCML, 1.5-V PCML, 2.5-V PCML, LVPECL, and LVDS									
Data rate (Standard PCS) ^{(9), (23)}	—	600	—	12200	600	—	12200	600	—	8500/ 10312.5 ⁽²⁴⁾	Mbps
Data rate (10G PCS) ^{(9), (23)}	—	600	—	14100	600	—	12500	600	—	8500/ 10312.5 ⁽²⁴⁾	Mbps
Absolute V_{MAX} for a receiver pin ⁽⁵⁾	—	—	—	1.2	—	—	1.2	—	—	1.2	V
Absolute V_{MIN} for a receiver pin	—	-0.4	—	—	-0.4	—	—	-0.4	—	—	V
Maximum peak-to-peak differential input voltage V_{ID} (diff p-p) before device configuration ⁽²²⁾	—	—	—	1.6	—	—	1.6	—	—	1.6	V
Maximum peak-to-peak differential input voltage V_{ID} (diff p-p) after device configuration ^{(18), (22)}	$V_{CCR_GXB} = 1.0\text{ V}/1.05\text{ V}$ ($V_{ICM} = 0.70\text{ V}$)	—	—	2.0	—	—	2.0	—	—	2.0	V
	$V_{CCR_GXB} = 0.90\text{ V}$ ($V_{ICM} = 0.6\text{ V}$)	—	—	2.4	—	—	2.4	—	—	2.4	V
	$V_{CCR_GXB} = 0.85\text{ V}$ ($V_{ICM} = 0.6\text{ V}$)	—	—	2.4	—	—	2.4	—	—	2.4	V
Minimum differential eye opening at receiver serial input pins ^{(6), (22), (27)}	—	85	—	—	85	—	—	85	—	—	mV

Table 23. Transceiver Specifications for Stratix V GX and GS Devices ⁽¹⁾ (Part 4 of 7)

Symbol/ Description	Conditions	Transceiver Speed Grade 1			Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Differential on-chip termination resistors ⁽²⁾	85- Ω setting	—	85 \pm 30%	—	—	85 \pm 30%	—	—	85 \pm 30%	—	Ω
	100- Ω setting	—	100 \pm 30%	—	—	100 \pm 30%	—	—	100 \pm 30%	—	Ω
	120- Ω setting	—	120 \pm 30%	—	—	120 \pm 30%	—	—	120 \pm 30%	—	Ω
	150- Ω setting	—	150 \pm 30%	—	—	150 \pm 30%	—	—	150 \pm 30%	—	Ω
V _{ICM} (AC and DC coupled)	V _{CCR_GXB} = 0.85 V or 0.9 V full bandwidth	—	600	—	—	600	—	—	600	—	mV
	V _{CCR_GXB} = 0.85 V or 0.9 V half bandwidth	—	600	—	—	600	—	—	600	—	mV
	V _{CCR_GXB} = 1.0 V/1.05 V full bandwidth	—	700	—	—	700	—	—	700	—	mV
	V _{CCR_GXB} = 1.0 V half bandwidth	—	750	—	—	750	—	—	750	—	mV
t _{LTR} ⁽¹¹⁾	—	—	—	10	—	—	10	—	—	10	μ s
t _{LTD} ⁽¹²⁾	—	4	—	—	4	—	—	4	—	—	μ s
t _{LTD_manual} ⁽¹³⁾	—	4	—	—	4	—	—	4	—	—	μ s
t _{LTR_LTD_manual} ⁽¹⁴⁾	—	15	—	—	15	—	—	15	—	—	μ s
Run Length	—	—	—	200	—	—	200	—	—	200	UI
Programmable equalization (AC Gain) ⁽¹⁰⁾	Full bandwidth (6.25 GHz) Half bandwidth (3.125 GHz)	—	—	16	—	—	16	—	—	16	dB

Table 28. Transceiver Specifications for Stratix V GT Devices (Part 1 of 5)⁽¹⁾

Symbol/ Description	Conditions	Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit	
		Min	Typ	Max	Min	Typ	Max		
Reference Clock									
Supported I/O Standards	Dedicated reference clock pin	1.2-V PCML, 1.4-V PCML, 1.5-V PCML, 2.5-V PCML, Differential LVPECL, LVDS, and HCSL							
	RX reference clock pin	1.4-V PCML, 1.5-V PCML, 2.5-V PCML, LVPECL, and LVDS							
Input Reference Clock Frequency (CMU PLL) ⁽⁶⁾	—	40	—	710	40	—	710	MHz	
Input Reference Clock Frequency (ATX PLL) ⁽⁶⁾	—	100	—	710	100	—	710	MHz	
Rise time	20% to 80%	—	—	400	—	—	400	ps	
Fall time	80% to 20%	—	—	400	—	—	400		
Duty cycle	—	45	—	55	45	—	55	%	
Spread-spectrum modulating clock frequency	PCI Express (PCIe)	30	—	33	30	—	33	kHz	
Spread-spectrum downspread	PCIe	—	0 to -0.5	—	—	0 to -0.5	—	%	
On-chip termination resistors ⁽¹⁹⁾	—	—	100	—	—	100	—	Ω	
Absolute V _{MAX} ⁽³⁾	Dedicated reference clock pin	—	—	1.6	—	—	1.6	V	
	RX reference clock pin	—	—	1.2	—	—	1.2		
Absolute V _{MIN}	—	-0.4	—	—	-0.4	—	—	V	
Peak-to-peak differential input voltage	—	200	—	1600	200	—	1600	mV	
V _{ICM} (AC coupled)	Dedicated reference clock pin	1050/1000 ⁽²⁾			1050/1000 ⁽²⁾			mV	
	RX reference clock pin	1.0/0.9/0.85 ⁽²²⁾			1.0/0.9/0.85 ⁽²²⁾			V	
V _{ICM} (DC coupled)	HCSL I/O standard for PCIe reference clock	250	—	550	250	—	550	mV	

Table 29 shows the V_{OD} settings for the GT channel.

Table 29. Typical V_{OD} Setting for GT Channel, TX Termination = 100 Ω

Symbol	V_{OD} Setting	V_{OD} Value (mV)
	0	0
	1	200
V_{OD} differential peak to peak typical ⁽¹⁾	2	400
	3	600
	4	800
	5	1000

Note:

(1) Refer to Figure 4.

Figure 6 shows the Stratix V DC gain curves for GT channels.

Figure 6. DC Gain Curves for GT Channels

Transceiver Characterization

This section summarizes the Stratix V transceiver characterization results for compliance with the following protocols:

- Interlaken
- 40G (XLAUI)/100G (CAUI)
- 10GBase-KR
- QSGMII
- XAUI
- SFI
- Gigabit Ethernet (Gbe / GIGE)
- SPAUI
- Serial Rapid IO (SRIO)
- CPRI
- OBSAI
- Hyper Transport (HT)
- SATA
- SAS
- CEI

Periphery Performance

This section describes periphery performance, including high-speed I/O and external memory interface.

I/O performance supports several system interfaces, such as the LVDS high-speed I/O interface, external memory interface, and the PCI/PCI-X bus interface.

General-purpose I/O standards such as 3.3-, 2.5-, 1.8-, and 1.5-LVTT/LVC MOS are capable of a typical 167 MHz and 1.2-LVC MOS at 100 MHz interfacing frequency with a 10 pF load.



The actual achievable frequency depends on design- and system-specific factors. Ensure proper timing closure in your design and perform HSPICE/IBIS simulations based on your specific design and system setup to determine the maximum achievable frequency in your system.

High-Speed I/O Specification

Table 36 lists high-speed I/O timing for Stratix V devices.

Table 36. High-Speed I/O Specifications for Stratix V Devices^{(1), (2)} (Part 1 of 4)

Symbol	Conditions	C1			C2, C2L, I2, I2L			C3, I3, I3L, I3YY			C4, I4			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
f _{HSCLK_in} (input clock frequency) True Differential I/O Standards	Clock boost factor W = 1 to 40 ⁽⁴⁾	5	—	800	5	—	800	5	—	625	5	—	525	MHz
f _{HSCLK_in} (input clock frequency) Single Ended I/O Standards ⁽³⁾	Clock boost factor W = 1 to 40 ⁽⁴⁾	5	—	800	5	—	800	5	—	625	5	—	525	MHz
f _{HSCLK_in} (input clock frequency) Single Ended I/O Standards	Clock boost factor W = 1 to 40 ⁽⁴⁾	5	—	520	5	—	520	5	—	420	5	—	420	MHz
f _{HSCLK_OUT} (output clock frequency)	—	5	—	800	5	—	800	5	—	625 ⁽⁵⁾	5	—	525 ⁽⁵⁾	MHz

Table 49. DCLK-to-DATA[] Ratio ⁽¹⁾ (Part 2 of 2)

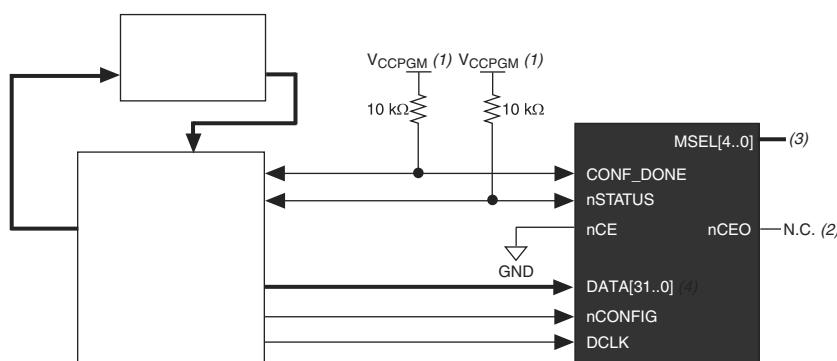
Configuration Scheme	Decompression	Design Security	DCLK-to-DATA[] Ratio
FPP ×32	Disabled	Disabled	1
	Disabled	Enabled	4
	Enabled	Disabled	8
	Enabled	Enabled	8

Note to Table 49:

- (1) Depending on the DCLK-to-DATA[] ratio, the host must send a DCLK frequency that is r times the data rate in bytes per second (Bps), or words per second (Wps). For example, in FPP ×16 when the DCLK-to-DATA[] ratio is 2, the DCLK frequency must be 2 times the data rate in Wps. Stratix V devices use the additional clock cycles to decrypt and decompress the configuration data.

 If the DCLK-to-DATA[] ratio is greater than 1, at the end of configuration, you can only stop the DCLK (DCLK-to-DATA[] ratio – 1) clock cycles after the last data is latched into the Stratix V device.

Figure 11 shows the configuration interface connections between the Stratix V device and a MAX II or MAX V device for single device configuration.

Figure 11. Single Device FPP Configuration Using an External Host**Notes to Figure 11:**

- (1) Connect the resistor to a supply that provides an acceptable input signal for the Stratix V device. V_{CCPGM} must be high enough to meet the V_{IH} specification of the I/O on the device and the external host. Altera recommends powering up all configuration system I/Os with V_{CCPGM}.
- (2) You can leave the nCEO pin unconnected or use it as a user I/O pin when it does not feed another device's nCE pin.
- (3) The MSEL pin settings vary for different data width, configuration voltage standards, and POR delay. To connect MSEL, refer to the MSEL Pin Settings section of the "Configuration, Design Security, and Remote System Upgrades in Stratix V Devices" chapter.
- (4) If you use FPP ×8, use DATA [7..0]. If you use FPP ×16, use DATA [15..0].

Table 50 lists the timing parameters for Stratix V devices for FPP configuration when the DCLK-to-DATA [] ratio is 1.

Table 50. FPP Timing Parameters for Stratix V Devices⁽¹⁾

Symbol	Parameter	Minimum	Maximum	Units
t_{CF2CD}	nCONFIG low to CONF_DONE low	—	600	ns
t_{CF2ST0}	nCONFIG low to nSTATUS low	—	600	ns
t_{CFG}	nCONFIG low pulse width	2	—	μs
t_{STATUS}	nSTATUS low pulse width	268	1,506 ⁽²⁾	μs
t_{CF2ST1}	nCONFIG high to nSTATUS high	—	1,506 ⁽³⁾	μs
$t_{CF2CK}^{(6)}$	nCONFIG high to first rising edge on DCLK	1,506	—	μs
$t_{ST2CK}^{(6)}$	nSTATUS high to first rising edge of DCLK	2	—	μs
t_{DSU}	DATA [] setup time before rising edge on DCLK	5.5	—	ns
t_{DH}	DATA [] hold time after rising edge on DCLK	0	—	ns
t_{CH}	DCLK high time	$0.45 \times 1/f_{MAX}$	—	s
t_{CL}	DCLK low time	$0.45 \times 1/f_{MAX}$	—	s
t_{CLK}	DCLK period	$1/f_{MAX}$	—	s
f_{MAX}	DCLK frequency (FPP ×8/×16)	—	125	MHz
	DCLK frequency (FPP ×32)	—	100	MHz
t_{CD2UM}	CONF_DONE high to user mode ⁽⁴⁾	175	437	μs
t_{CD2CU}	CONF_DONE high to CLKUSR enabled	$4 \times$ maximum DCLK period	—	—
t_{CD2UMC}	CONF_DONE high to user mode with CLKUSR option on	$t_{CD2CU} +$ $(8576 \times$ CLKUSR period) ⁽⁵⁾	—	—

Notes to Table 50:

- (1) Use these timing parameters when the decompression and design security features are disabled.
- (2) This value is applicable if you do not delay configuration by extending the nCONFIG or nSTATUS low pulse width.
- (3) This value is applicable if you do not delay configuration by externally holding the nSTATUS low.
- (4) The minimum and maximum numbers apply only if you chose the internal oscillator as the clock source for initializing the device.
- (5) To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on these pins, refer to the Initialization section of the “Configuration, Design Security, and Remote System Upgrades in Stratix V Devices” chapter.
- (6) If nSTATUS is monitored, follow the t_{ST2CK} specification. If nSTATUS is not monitored, follow the t_{CF2CK} specification.

FPP Configuration Timing when DCLK-to-DATA [] > 1

Figure 13 shows the timing waveform for FPP configuration when using a MAX II device, MAX V device, or microprocessor as an external host. This waveform shows timing when the DCLK-to-DATA [] ratio is more than 1.

Table 51 lists the timing parameters for Stratix V devices for FPP configuration when the DCLK-to-DATA [] ratio is more than 1.

Table 51. FPP Timing Parameters for Stratix V Devices When the DCLK-to-DATA[] Ratio is >1⁽¹⁾

Symbol	Parameter	Minimum	Maximum	Units
t_{CF2CD}	nCONFIG low to CONF_DONE low	—	600	ns
t_{CF2ST0}	nCONFIG low to nSTATUS low	—	600	ns
t_{CFG}	nCONFIG low pulse width	2	—	μs
t_{STATUS}	nSTATUS low pulse width	268	1,506 ⁽²⁾	μs
t_{CF2ST1}	nCONFIG high to nSTATUS high	—	1,506 ⁽²⁾	μs
$t_{CF2CK}^{(5)}$	nCONFIG high to first rising edge on DCLK	1,506	—	μs
$t_{ST2CK}^{(5)}$	nSTATUS high to first rising edge of DCLK	2	—	μs
t_{DSU}	DATA [] setup time before rising edge on DCLK	5.5	—	ns
t_{DH}	DATA [] hold time after rising edge on DCLK	$N-1/f_{DCLK}^{(5)}$	—	s
t_{CH}	DCLK high time	$0.45 \times 1/f_{MAX}$	—	s
t_{CL}	DCLK low time	$0.45 \times 1/f_{MAX}$	—	s
t_{CLK}	DCLK period	$1/f_{MAX}$	—	s
f_{MAX}	DCLK frequency (FPP ×8/×16)	—	125	MHz
	DCLK frequency (FPP ×32)	—	100	MHz
t_R	Input rise time	—	40	ns
t_F	Input fall time	—	40	ns
t_{CD2UM}	CONF_DONE high to user mode ⁽³⁾	175	437	μs
t_{CD2CU}	CONF_DONE high to CLKUSR enabled	$4 \times$ maximum DCLK period	—	—
t_{CD2UMC}	CONF_DONE high to user mode with CLKUSR option on	$t_{CD2CU} + (8576 \times$ CLKUSR period) ⁽⁴⁾	—	—

Notes to Table 51:

- (1) Use these timing parameters when you use the decompression and design security features.
- (2) You can obtain this value if you do not delay configuration by extending the nCONFIG or nSTATUS low pulse width.
- (3) The minimum and maximum numbers apply only if you use the internal oscillator as the clock source for initializing the device.
- (4) To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on these pins, refer to the Initialization section of the “Configuration, Design Security, and Remote System Upgrades in Stratix V Devices” chapter.
- (5) N is the DCLK-to-DATA ratio and f_{DCLK} is the DCLK frequency the system is operating.
- (6) If nSTATUS is monitored, follow the t_{ST2CK} specification. If nSTATUS is not monitored, follow the t_{CF2CK} specification.

Table 58. IOE Programmable Delay for Stratix V Devices (Part 2 of 2)

Parameter (1)	Available Settings	Min Offset (2)	Fast Model		Slow Model							
			Industrial	Commercial	C1	C2	C3	C4	I2	I3, I3YY	I4	Unit
D3	8	0	1.587	1.699	2.793	2.793	2.992	3.192	2.811	3.047	3.257	ns
D4	64	0	0.464	0.492	0.838	0.838	0.924	1.011	0.843	0.920	1.006	ns
D5	64	0	0.464	0.493	0.838	0.838	0.924	1.011	0.844	0.921	1.006	ns
D6	32	0	0.229	0.244	0.415	0.415	0.458	0.503	0.418	0.456	0.499	ns

Notes to Table 58:

- (1) You can set this value in the Quartus II software by selecting **D1**, **D2**, **D3**, **D5**, and **D6** in the **Assignment Name** column of **Assignment Editor**.
(2) Minimum offset does not include the intrinsic delay.

Programmable Output Buffer Delay

Table 59 lists the delay chain settings that control the rising and falling edge delays of the output buffer. The default delay is 0 ps.

Table 59. Programmable Output Buffer Delay for Stratix V Devices (1)

Symbol	Parameter	Typical	Unit
D_{OUTBUF}	Rising and/or falling edge delay	0 (default)	ps
		25	ps
		50	ps
		75	ps

Note to Table 59:

- (1) You can set the programmable output buffer delay in the Quartus II software by setting the **Output Buffer Delay Control** assignment to either positive, negative, or both edges, with the specific values stated here (in ps) for the **Output Buffer Delay** assignment.

Glossary

Table 60 lists the glossary for this chapter.

Table 60. Glossary (Part 1 of 4)

Letter	Subject	Definitions
A	—	—
B	—	—
C	—	—
D	—	—
E	—	—
F	f_{HSCLK}	Left and right PLL input clock frequency.
	f_{HSDR}	High-speed I/O block—Maximum and minimum LVDS data transfer rate ($f_{HSDR} = 1/TUI$), non-DPA.
	$f_{HSDRDPA}$	High-speed I/O block—Maximum and minimum LVDS data transfer rate ($f_{HSDRDPA} = 1/TUI$), DPA.

Table 60. Glossary (Part 2 of 4)

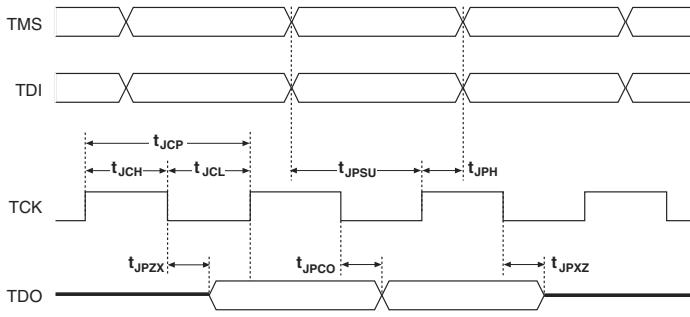
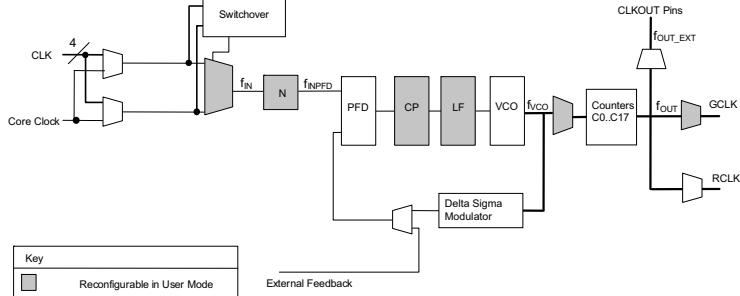
Letter	Subject	Definitions
G H I	—	—
J	J	High-speed I/O block—Deserialization factor (width of parallel data bus).
J	JTAG Timing Specifications	JTAG Timing Specifications: 
		—
K L M N O	—	—
P	PLL Specifications	<p>Diagram of PLL Specifications (1)</p>  <p>Note: (1) Core Clock can only be fed by dedicated clock input pins or PLL outputs.</p>
Q	—	—
R	R_L	Receiver differential input discrete resistor (external to the Stratix V device).

Table 61. Document Revision History (Part 2 of 3)

Date	Version	Changes
November 2014	3.3	<ul style="list-style-type: none"> ■ Added the I3YY speed grade and changed the data rates for the GX channel in Table 1. ■ Added the I3YY speed grade to the V_{CC} description in Table 6. ■ Added the I3YY speed grade to V_{CCHIP_L}, V_{CCHIP_R}, V_{CCHSSI_L}, and V_{CCHSSI_R} descriptions in Table 7. ■ Added 240-Ω to Table 11. ■ Changed CDR PPM tolerance in Table 23. ■ Added additional max data rate for fPLL in Table 23. ■ Added the I3YY speed grade and changed the data rates for transceiver speed grade 3 in Table 25. ■ Added the I3YY speed grade and changed the data rates for transceiver speed grade 3 in Table 26. ■ Changed CDR PPM tolerance in Table 28. ■ Added additional max data rate for fPLL in Table 28. ■ Changed the mode descriptions for MLAB and M20K in Table 33. ■ Changed the Max value of f_{HSCLK_OUT} for the C2, C2L, I2, I2L speed grades in Table 36. ■ Changed the frequency ranges for C1 and C2 in Table 39. ■ Changed the .rbf file sizes for 5SGSD6 and 5SGSD8 in Table 47. ■ Added note about nSTATUS to Table 50, Table 51, Table 54. ■ Changed the available settings in Table 58. ■ Changed the note in “Periphery Performance”. ■ Updated the “I/O Standard Specifications” section. ■ Updated the “Raw Binary File Size” section. ■ Updated the receiver voltage input range in Table 22. ■ Updated the max frequency for the LVDS clock network in Table 36. ■ Updated the DCLK note to Figure 11. ■ Updated Table 23 VO_{CM} (DC Coupled) condition. ■ Updated Table 6 and Table 7. ■ Added the DCLK specification to Table 55. ■ Updated the notes for Table 47. ■ Updated the list of parameters for Table 56.
November 2013	3.2	<ul style="list-style-type: none"> ■ Updated Table 28
November 2013	3.1	<ul style="list-style-type: none"> ■ Updated Table 33
November 2013	3.0	<ul style="list-style-type: none"> ■ Updated Table 23 and Table 28
October 2013	2.9	<ul style="list-style-type: none"> ■ Updated the “Transceiver Characterization” section
October 2013	2.8	<ul style="list-style-type: none"> ■ Updated Table 3, Table 12, Table 14, Table 19, Table 20, Table 23, Table 24, Table 28, Table 30, Table 31, Table 32, Table 33, Table 36, Table 39, Table 40, Table 41, Table 42, Table 47, Table 53, Table 58, and Table 59 ■ Added Figure 1 and Figure 3 ■ Added the “Transceiver Characterization” section ■ Removed all “Preliminary” designations.

Table 61. Document Revision History (Part 3 of 3)

Date	Version	Changes
May 2013	2.7	<ul style="list-style-type: none"> ■ Updated Table 2, Table 6, Table 7, Table 20, Table 23, Table 27, Table 47, Table 60 ■ Added Table 24, Table 48 ■ Updated Figure 9, Figure 10, Figure 11, Figure 12
February 2013	2.6	<ul style="list-style-type: none"> ■ Updated Table 7, Table 9, Table 20, Table 23, Table 27, Table 30, Table 31, Table 35, Table 46 ■ Updated “Maximum Allowed Overshoot and Undershoot Voltage”
December 2012	2.5	<ul style="list-style-type: none"> ■ Updated Table 3, Table 6, Table 7, Table 8, Table 23, Table 24, Table 25, Table 27, Table 30, Table 32, Table 35 ■ Added Table 33 ■ Added “Fast Passive Parallel Configuration Timing” ■ Added “Active Serial Configuration Timing” ■ Added “Passive Serial Configuration Timing” ■ Added “Remote System Upgrades” ■ Added “User Watchdog Internal Circuitry Timing Specification” ■ Added “Initialization” ■ Added “Raw Binary File Size”
June 2012	2.4	<ul style="list-style-type: none"> ■ Added Figure 1, Figure 2, and Figure 3. ■ Updated Table 1, Table 2, Table 3, Table 6, Table 11, Table 22, Table 23, Table 27, Table 29, Table 30, Table 31, Table 32, Table 35, Table 38, Table 39, Table 40, Table 41, Table 43, Table 56, and Table 59. ■ Various edits throughout to fix bugs. ■ Changed title of document to <i>Stratix V Device Datasheet</i>. ■ Removed document from the Stratix V handbook and made it a separate document.
February 2012	2.3	<ul style="list-style-type: none"> ■ Updated Table 1–22, Table 1–29, Table 1–31, and Table 1–31.
December 2011	2.2	<ul style="list-style-type: none"> ■ Added Table 2–31. ■ Updated Table 2–28 and Table 2–34.
November 2011	2.1	<ul style="list-style-type: none"> ■ Added Table 2–2 and Table 2–21 and updated Table 2–5 with information about Stratix V GT devices. ■ Updated Table 2–11, Table 2–13, Table 2–20, and Table 2–25. ■ Various edits throughout to fix SPRs.
May 2011	2.0	<ul style="list-style-type: none"> ■ Updated Table 2–4, Table 2–18, Table 2–19, Table 2–21, Table 2–22, Table 2–23, and Table 2–24. ■ Updated the “DQ Logic Block and Memory Output Clock Jitter Specifications” title. ■ Chapter moved to Volume 1. ■ Minor text edits.
December 2010	1.1	<ul style="list-style-type: none"> ■ Updated Table 1–2, Table 1–4, Table 1–19, and Table 1–23. ■ Converted chapter to the new template. ■ Minor text edits.
July 2010	1.0	Initial release.